

**Structure Development in Polymers during Fused Filament Fabrication (FFF): An in-situ Small and Wide Angle X-ray Scattering Study using Synchrotron Radiation**

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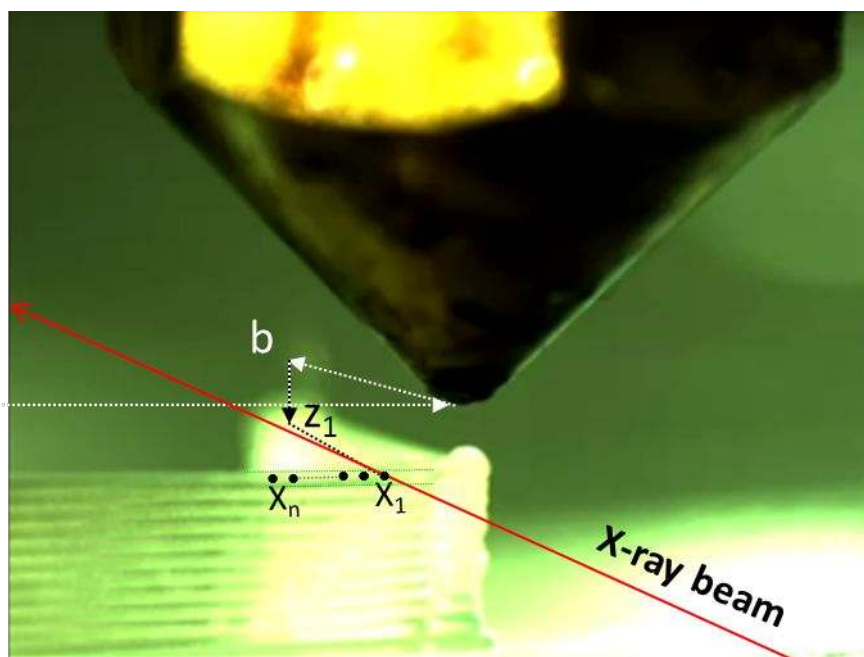
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## Supporting information

**Movie SI1:** SI1\_3D\_Printing\_1.wlmp (Movie of a 3D printing experiment, the movie has been fast-forwarded)

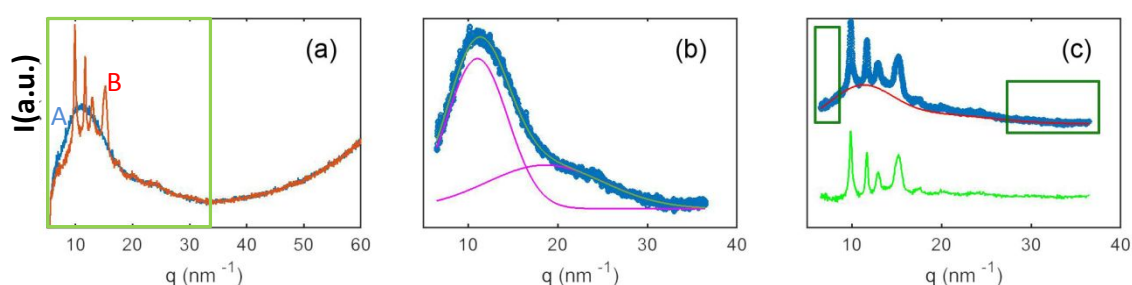
## Experimental procedure



**Figure SI\_1.** Scheme of the experimental procedure. For every measurement, a  $\Pi$ -shaped five-layer single-walled sample was 3D printed under fixed conditions which were optimized in a series of ex-situ studies to produce samples with an adequate mechanical stability. After printing a  $\Pi$ -shaped five-layer single-walled sample (long side 5.92 cm, short side 0.5 cm), i.e. when the printing head reached the position  $b$ , the nozzle stopped extrusion, the filament was retracted, the substrate moved down  $Z_1 = 0.050$  cm and the build platform moved with a travel speed of 14 cm/s to the selected measurement position,  $X_i$ . Once the selected measurement position has been reached the data acquisition was triggered and SAXS and WAXS data were acquired as a function of time.

### Calculation of the crystallinity degree from the WAXS patterns.

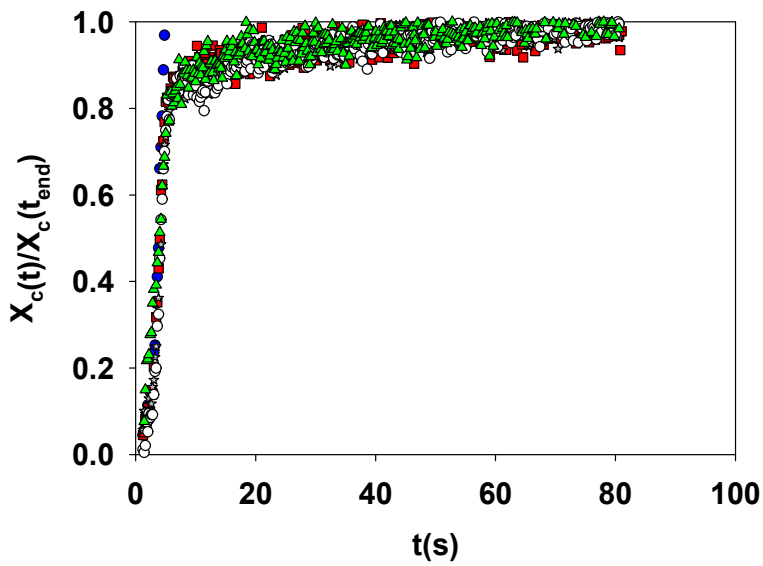
The crystallinity was calculated by means of a fit parameter study proposed by Blundell and Osborn<sup>26, 28</sup>. Figure SI\_2a shows the azimuthally integrated scattered intensity as a function of the modulus of the scattering vector  $q$  as-calculated from the corresponding WAXS patterns obtained from the first frames (when polymer has not crystallized, A(blue pattern)) and final frames (when polymer has crystallized, B(red pattern)) in a given experiment.



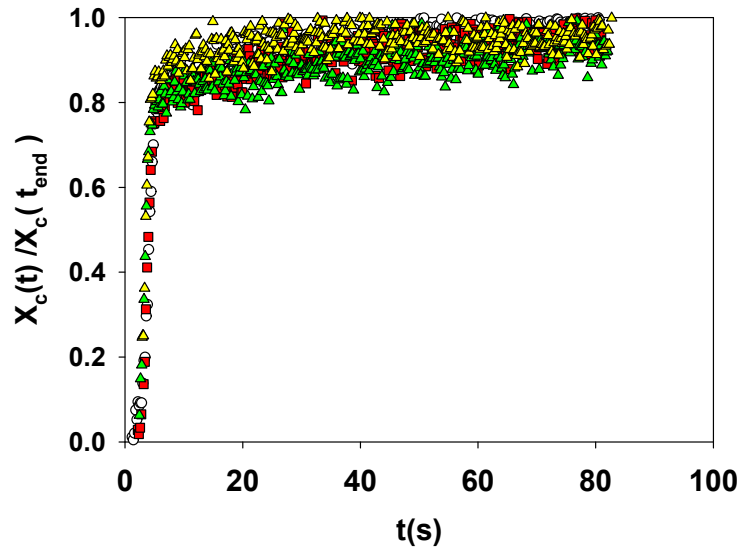
**Figure SI\_2.** (a) An example of the azimuthally integrated scattered intensity as a function of the modulus of the scattering vector  $q$  as-calculated from the corresponding WAXS patterns for an initially amorphous polymer, A(blue pattern), and eventually semicrystalline, (B, red pattern), sample. (b) An example of an amorphous halo fitted by two Gaussian functions. (c) An example of an intermediate state where the contribution of the amorphous halo can be deconvoluted from the contribution of the Bragg peaks. The green rectangles in (c) indicate the  $q$ -region where both amorphous halo and measured data should coincide.

The green rectangle in Fig. SI\_2a indicates the data range we used for the calculation. After the background correction the intensity was fitted by two Gaussian functions (Figure SI\_2b). In general, every frame was considered to be composed of: (i) the amorphous halo (multiplied by a scaling factor lower than unity), (ii) the amorphous

phase, (iii) the crystalline phase (Figure SI\_2c). To calculate the scaling factor for the contribution of the amorphous halo we used the low and high  $q$  regions which are highlighted by the green rectangles in Figure SI\_2c, where the Bragg peaks have the least contribution. The crystalline contribution is considered to be the difference between the calculated halo and the total signal (see the bottom curve in Figure SI\_2c). The fit parameter study was performed using a self-written code implemented in Matlab®.



**Figure SI\_3.** Degree of transformation as derived from crystallinity data across the layer of Fig. 5a normalized by the final crystallinity value. The measurements were performed in different  $Z$  positions across the top layer in a five-layer sample: on the free surface ( $\bullet$ ); 0.005 cm ( $\blacksquare$ ), 0.010 cm, ( $\star$ ), 0.015 cm ( $\circ$ ), 0.020 cm ( $\blacktriangle$ ).



*Figure SI\_4. Degree of transformation as derived from crystallinity data along the layer of Fig. 7a normalized by the final crystallinity value. The measurements were performed in four different positions along the top layer in a five-layer sample: 0.10 cm (○), 0.90 cm (■), 1.40 cm (▼), and 1.90 cm (▲) from to the edge of the  $\Pi$ -sample, respectively.*